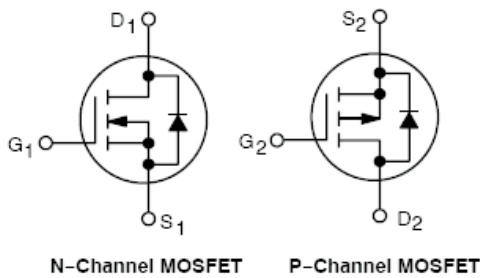
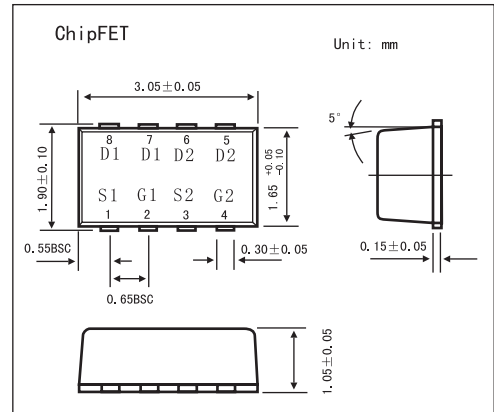


KTHD3100C

■ Features

- Complementary N-Channel and P-Channel MOSFET
- Leadless SMD Package Provides Great Thermal Characteristics
- Trench P-Channel for Low On Resistance
- Low Gate Charge N-Channel for Test Switching



■ Absolute Maximum Ratings Ta = 25°C

Parameter	Symbol	N-Channel	P-Channel	Unit
Drain-source voltage	V _{DSS}	20		V
Gate-source voltage	V _{GSS}	±12	±8.0	V
Drain current Continuous *1 TA = 25°C TA = 85°C t ≤ 10s	I _D	2.9	-3.2	A
		2.1	-2.3	
		3.9	-4.4	
Drain current Pulsed t = 10 μs *1	I _{DM}	12	-13	A
Total power dissipation t ≤ 5s	P _D	1.1		W
		3.1		W
Operating and Storage Temperature Range	T _J , T _{stg}	-55 to 150		°C
Source Current (Body Diode)	I _S	2.5		A
Lead Temperature for Soldering Purposes	T _L	260		°C
Junction-to-Ambient *1	R _{θJA}	Steady State		°C/W
		t ≤ 10s		
		113		
		60		

*1 Surface Mounted on FR4 board using 1 in sq pad size

■ Electrical Characteristics Ta = 25°C

Parameter	Symbol	Testconditions	Min	Typ	Max	Unit	
Drain-source breakdown voltage	V _{(BR)DSS}	I _D =250 μ A, V _{GS} =0V	N-Ch	20		V	
		I _D =-250 μ A, V _{GS} =0V	P-Ch	-20			
Zero gate voltage drain current	I _{DSS}	V _{DS} =16V, V _{GS} =0V	N-Ch		1	μ A	
		V _{DS} =16V, V _{GS} =0V, T _J = 25°C			5.0		
		V _{DS} =-16V, V _{GS} =0V	P-Ch		-1		
		V _{DS} =-16V, V _{GS} =0V, T _J = 125°C			-5		
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _{GS} = ± 12 V	N-Ch		± 100	nA	
		V _{DS} = 0 V, V _{GS} = ± 8 V	P-Ch		± 100		
Gate threshold voltage *1	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250 μ A	N-Ch	0.6	1.2	V	
		V _{DS} = V _{GS} , I _D = -250 μ A	P-Ch	-0.45	-1.5		
Static drain-source on-state resistance *1	R _{DS(on)}	I _D =2.9A, V _{GS} =4.5A	N-Ch		58	80	m Ω
		I _D =2.3A, V _{GS} =2.5V			77	115	
Static drain-source on-state resistance *1	R _{DS(on)}	I _D =-3.2A, V _{GS} =-4.5V	P-Ch		64	80	m Ω
		I _D =-2.2A, V _{GS} =-2.5V			85	110	
Forward Transconductance	g _{FS}	I _D =2.9A, V _{DS} =10V	N-Ch	6.0		S	
		I _D =-3.2A, V _{DS} =-10V	P-Ch	8.0			
Input capacitance	C _{iss}	N-Channel V _{DS} =10V, V _{GS} =0V, f=1MHz	N-Ch	165		pF	
			P-Ch	680			
Output capacitance	C _{oss}	P-Channel	N-Ch	80		pF	
			P-Ch	100			
Reverse transfer capacitance	C _{rss}	V _{DS} =-10V, V _{GS} =0V, f=1MHz	N-Ch	25		pF	
			P-Ch	70			
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 4.5 V, V _{DS} = 10 V, I _D = 2.9 A	N-Ch	2.3		nC	
		V _{GS} =-4.5 V, V _{DS} = -10 V, I _D =-3.2 A	P-Ch	7.4			
Threshold Gate Charge	Q _{G(TH)}	V _{GS} = 4.5 V, V _{DS} = 10 V, I _D = 2.9 A	N-Ch	0.2		nC	
		V _{GS} =-4.5 V, V _{DS} = -10 V, I _D =-3.2 A	P-Ch	0.6			
Gate-to-Source Gate Charge	Q _{GS}	V _{GS} = 4.5 V, V _{DS} = 10 V, I _D = 2.9 A	N-Ch	0.4		nC	
		V _{GS} =-4.5 V, V _{DS} =-10 V, I _D =-3.2 A	P-Ch	1.4			
Gate-to-Drain "Miller" Charge	Q _{GD}	V _{GS} = 4.5 V, V _{DS} = 10 V, I _D = 2.9 A	N-Ch	0.7		nC	
		V _{GS} =-4.5 V, V _{DS} =-10 V, I _D =-3.2 A	P-Ch	2.5			
Turn-on delay time	t _{d(on)}	I _D =2.9A, V _{DD} =10V	N-Ch	6.3		ns	
		I _D =-3.2A, V _{DD} =-10V	P-Ch	5.8			
Rise time	t _r	N-Channel V _{GS} =4.5V, R _G =2.5 Ω *2	N-Ch	10.7		ns	
			P-Ch	11.7			
Turn-off delay time *1	t _{d(off)}	P-Channel	N-Ch	9.6		ns	
			P-Ch	16			
Fall time *1	t _f	V _{GS} =-4.5V, R _G =2.5 Ω *2	N-Ch	1.5		ns	
			P-Ch	12.4			
Forward Voltage *1	V _{SD}	I _S =2.5 A, V _{GS} =0V	N-Ch	0.8	1.15	V	
		I _S =-2.5 A, V _{GS} =0 V	P-Ch	-0.8	-1.2		



KTHD3100C

■ Electrical Characteristics Ta = 25°C

Parameter	Symbol	Testconditons	Min	Typ	Max	Unit	
Reverse Recovery Time	trr	VGS = 0 V,dis/dt = 100 A/μs,Is=1.5 A	N-Ch		12.5		ns
			P-Ch		13.5		
	ta		N-Ch		9		
			P-Ch		9.5		
	tb		N-Ch		3.5		
			P-Ch		4		
Reverse Recovery Storage Charge	QRR	VGS = 0 V,dis/dt = 100 A/μs,Is=?1.5A	N-Ch		6		nC
			P-Ch		6.5		

*1 Pulse Test: Pulse Width ≤250 μs, Duty Cycle ≤2%.

*2 Switching characteristics are independent of operating junction temperature.